

STN1N20

N-channel 200 V, 1.2 Ω, 1 A, SOT-223 MESH OVERLAY™ Power MOSFET

Features

| Туре | V _{DSS} | R _{DS(on)} max | I _D |
|---------|------------------|-------------------------|----------------|
| STN1N20 | 200 V | < 1.5 Ω | 1 A |

■ 100% avalanche tested

Application

■ Switching applications

Description

Using the latest high voltage MESH OVERLAYTM process, STMicroelectronics has designed an advanced family of power MOSFETs with outstanding performance. The new patented STrip layout coupled with the company's proprietary edge termination structure, makes it suitable in converters for lighting applications.

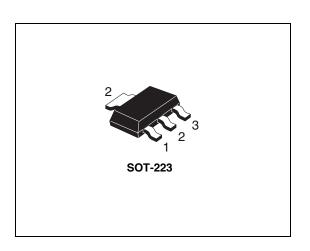


Figure 1. Internal schematic diagram

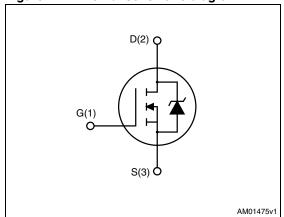


Table 1. Device summary

| Order codes | Marking | Package | Packaging |
|-------------|---------|---------|---------------|
| STN1N20 | N1N20 | SOT-223 | Tape and reel |

April 2009 Rev 2 1/12

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STN1N20 Electrical ratings

1 Electrical ratings

Table 2. Absolute maximum ratings

| Symbol | Parameter | Value | Unit |
|------------------------------------|---|------------|------|
| V _{DS} | Drain-source voltage (V _{GS} =0) | 200 | V |
| V_{GS} | Gate-source voltage | ± 20 | V |
| I _D | Drain current (continuous) at T _C = 25 °C | 1 | Α |
| I _D | Drain current (continuous) at T _C = 100 °C | 0.6 | Α |
| I _{DM} ⁽¹⁾ | Drain current (pulsed) | 4 | Α |
| P _{TOT} | Total dissipation at T _C = 25 °C | 2.9 | W |
| | Derating factor | 0.023 | W/°C |
| dv/dt | Peak diode recovery voltage slope | 6 | V/ns |
| T _j T _{stg} | Operating junction temperature Storage temperature | -55 to 150 | °C |

^{1.} Pulse width limited by safe operating area

Table 3. Thermal data

| Symbol | Parameter | Value | Unit |
|----------------------|--|-------|------|
| R _{thj-pcb} | Thermal resistance junction-pcb max | 43 | °C/W |
| R _{thj-amb} | Thermal resistance junction-ambient max | 60 | °C/W |
| T _I | Maximum lead temperature for soldering purpose | 260 | °C |

Table 4. Thermal data

| Symbol | Parameter | Value | Unit |
|-----------------|---|-------|------|
| I _{AR} | Max current during repetitive or single pulse avalanche (pulse width limited by T _{JMAX}) | 1 | A |
| E _{AS} | Single pulse avalanche energy (1) | 10 | mJ |

^{1.} Starting T_j = 25 °C, I_D = I_{AR} , V_{DD} = 50 V

Electrical characteristics STN1N20

2 Electrical characteristics

(Tcase = 25 °C unless otherwise specified)

Table 5. On /off states

| Symbol | Parameter | Test conditions | Min. | Тур. | Max. | Unit |
|----------------------|---|---|------|------|----------|--------------------------|
| V _{(BR)DSS} | Drain-source breakdown voltage | $I_D = 250 \mu A, V_{GS} = 0$ | 200 | | | V |
| I _{DSS} | | V_{DS} = Max rating V_{DS} = Max rating, T_{C} =125 °C | | | 1 100 | μ Α μ Α |
| I _{GSS} | Gate-body leakage current (V _{DS} = 0) | V _{GS} = ± 20 V | | | ±100 | nA |
| V _{GS(th)} | Gate threshold voltage | $V_{DS} = V_{GS}, I_{D} = 250 \mu A$ | 3 | 4 | 5 | V |
| R _{DS(on)} | Static drain-source on resistance | $V_{GS} = 10 \text{ V}, I_D = 0.5 \text{ A}$ | | 1.2 | 1.5 | Ω |

Table 6. Dynamic

| Symbol | Parameter | Test conditions | Min. | Тур. | Max. | Unit |
|--|---|--|------|-----------------|------|----------------|
| 9 _{fs} ⁽¹⁾ | Forward transconductance | $V_{DS} > I_{D(on)} \times R_{DS(on)max},$ $I_{D} = 0.5 \text{ A}$ | | 2.7 | | S |
| C _{iss} C _{oss} C _{rss} | Input capacitance Output capacitance Reverse transfer capacitance | $V_{DS} = 25 \text{ V, f} = 1 \text{ MHz,}$ $V_{GS} = 0$ | | 206 40 15 | | pF pF pF |
| Q _g Q _{gs} Q _{gd} | Total gate charge Gate-source charge Gate-drain charge | V_{DD} = 160 V, I_D = 4 A, V_{GS} = 10 V (see <i>Figure 14</i>) | | 11 2.8 4 | 15.7 | nC nC nC |

^{1.} Pulsed: pulse duration = 300 μ s, duty cycle 1.5%

Table 7. Switching times

| | J | | | | | |
|--|--|--|------|--------------------|-----|----------------------|
| Symbol | Parameter | Test conditions | Min. | Тур. | Max | Unit |
| t _{d(on)} t _r t _{d(off)} t _f | Turn-on delay time Rise time Turn-off delay time Fall time | $V_{DD} = 160 \text{ V}, I_D = 4 \text{ A},$ $R_G = 4.7 \Omega, V_{GS} = 10 \text{ V}$ (see <i>Figure 13</i>) | | 9 10 25 6 | | ns ns ns ns |

Table 8. Source drain diode

| Symbol | Parameter | Test conditions | Min. | Тур. | Max. | Unit |
|--|--|--|------|-------------------|--------|---------------|
| I _{SD} | Source-drain current Source-drain current (pulsed) | | | | 1 4 | A A |
| V _{SD} (2) | Forward on voltage | I _{SD} = 1 A, V _{GS} = 0 | | | 1.5 | ٧ |
| t _{rr} Q _{rr} I _{RRM} | Reverse recovery time Reverse recovery charge Reverse recovery current | $I_{SD} = 4$ A, di/dt = 100 A/ μ s $V_{DD} = 30$ V, $T_j = 150$ °C (see <i>Figure 18</i>) | | 124 446 7.2 | | ns nC A |

^{1.} Pulse width limited by safe operating area

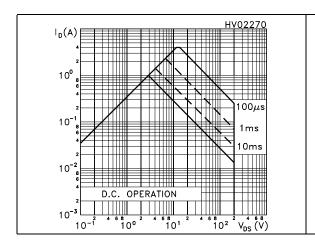
^{2.} Pulsed: Pulse duration = 300 μs, duty cycle 1.5%

Electrical characteristics STN1N20

2.1 Electrical characteristics (curves)

Figure 2. Safe operating area

Figure 3. Thermal impedance



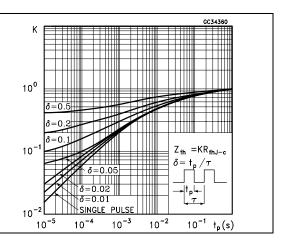
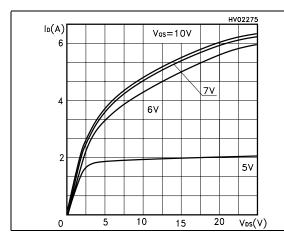


Figure 4. Output characteristics

Figure 5. Transfer characteristics



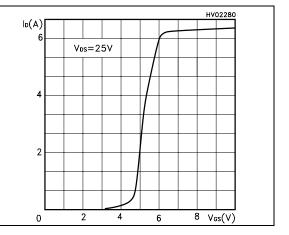


Figure 6. Transconductance

Figure 7. Static drain-source on resistance

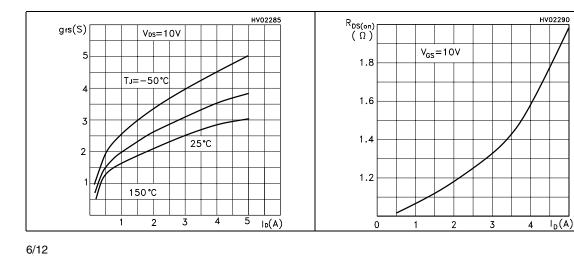


Figure 8. Gate charge vs gate-source voltage Figure 9. Capacitance variations

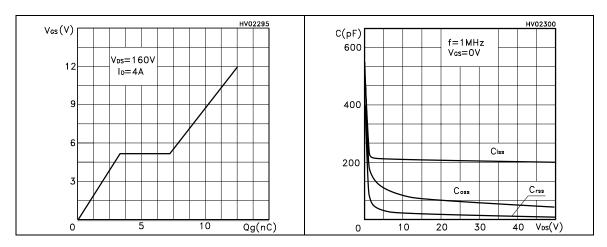


Figure 10. Normalized gate threshold voltage Figure 11. Normalized on resistance vs vs temperature temperature

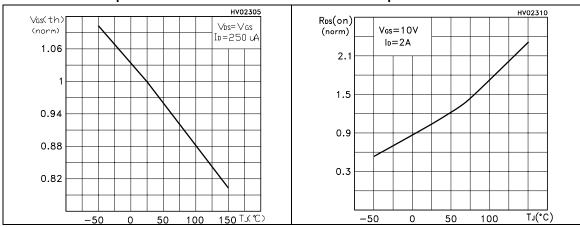
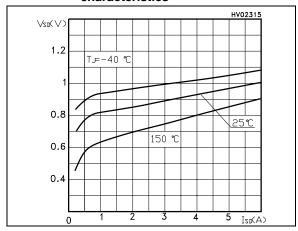


Figure 12. Source-drain diode forward characteristics



Test circuits STN1N20

3 Test circuits

Figure 13. Switching times test circuit for resistive load

Figure 14. Gate charge test circuit

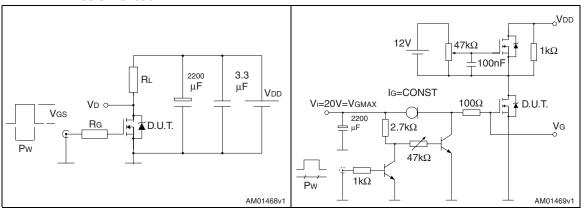


Figure 15. Test circuit for inductive load switching and diode recovery times

Figure 16. Unclamped inductive load test circuit

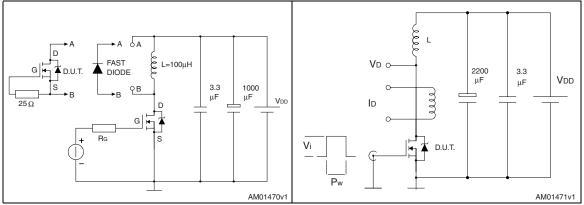
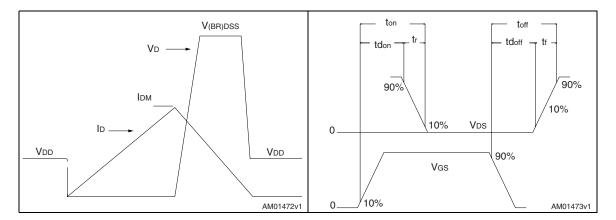


Figure 17. Unclamped inductive waveform

Figure 18. Switching time waveform



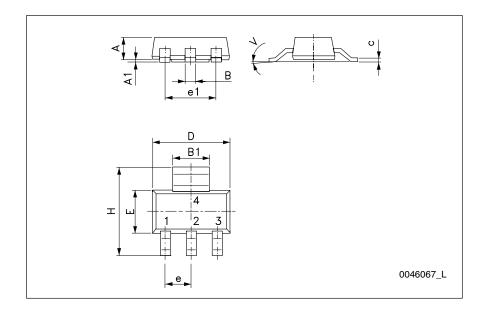
4 Package mechanical data

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK[®] packages, depending on their level of environmental compliance. ECOPACK[®] specifications, grade definitions and product status are available at: www.st.com. ECOPACK is an ST trademark.

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| COT | 222 | maak | nanic | ما ماما | ۱. |
|-----|------|------|--------|---------|------|
| SUL | -223 | mecr | ianica | ai dai | ia - |

| DIM. | | mm. | |
|--------|------|------|------|
| DIIVI. | min. | typ | max. |
| Α | | | 1.80 |
| A1 | 0.02 | | 0.1 |
| В | 0.60 | 0.70 | 0.85 |
| B1 | 2.90 | 3.00 | 3.15 |
| С | 0.24 | 0.26 | 0.35 |
| D | 6.30 | 6.50 | 6.70 |
| е | | 2.30 | |
| e1 | | 4.60 | |
| E | 3.30 | 3.50 | 3.70 |
| Н | 6.70 | 7.00 | 7.30 |
| V | | | 10 ° |



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STN1N20 Revision history

5 Revision history

Table 9. Document revision history

| Date | Revision | Changes |
|-------------|----------|--|
| 21-Jun-2004 | 1 | First release. |
| 31-Mar-2009 | 2 | Document status promoted from preliminary data to datasheet. |

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